

RoHS Compliant Product
A suffix of "-C" specifies halogen free

DESCRIPTION

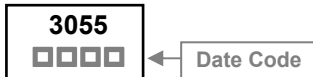
The SSD3055R-C is the highest performance trench N-ch MOSFETs with extreme high cell density, which provide excellent $R_{DS(on)}$ and gate charge for most of the synchronous buck converter applications.

The SSD3055R-C meet the RoHS and Green Product requirement with full function reliability approved.

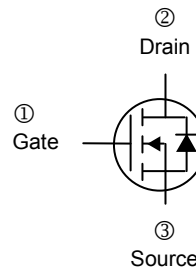
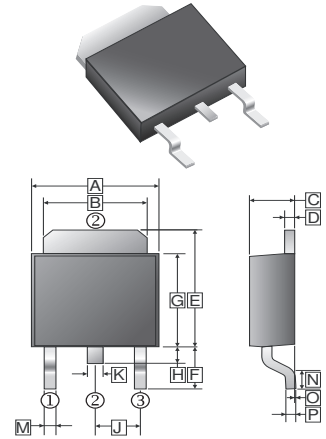
FEATURES

- Advanced High Cell Density Trench Technology
- Super Low Gate Charge
- Excellent CdV/dt Effect Decline
- Green Device Available

MARKING



TO-252(D-Pack)



REF.	Millimeter		REF.	Millimeter	
	Min.	Max.		Min.	Max.
A	6.30	6.90	J	2.30	REF.
B	4.95	5.53	K	0.89	REF.
C	2.10	2.50	M	0.45	1.14
D	0.40	0.90	N	1.55	TYP.
E	6.00	7.70	O	0	0.15
F	2.90	REF.	P	0.58	REF.
G	5.40	6.40			
H	0.60	1.20			

PACKAGE INFORMATION

Package	MPQ	Leader Size
TO-252	2.5K	13 inch

ORDER INFORMATION

Part Number	Type
SSD3055R-C	Lead (Pb)-free and Halogen-free

ABSOLUTE MAXIMUM RATINGS ($T_A=25^\circ\text{C}$ unless otherwise specified)

Parameter	Symbol	Rating	Unit
Drain-Source Voltage	V_{DS}	30	V
Gate-Source Voltage	V_{GS}	± 20	V
Continuous Drain Current @ $V_{GS}=10\text{V}$ ¹	$T_C=25^\circ\text{C}$	30	A
	$T_C=100^\circ\text{C}$	18	
	$T_A=25^\circ\text{C}$	8.2	
	$T_A=70^\circ\text{C}$	6.5	
Pulsed Drain Current ²	I_{DM}	60	A
Total Power Dissipation ³	$T_C=25^\circ\text{C}$	25	W
	$T_A=25^\circ\text{C}$	2	
Operating Junction and Storage Temperature Range	T_J, T_{STG}	-55~150	$^\circ\text{C}$
Thermal Resistance Rating			
Maximum Thermal Resistance Junction-Ambient ¹	$R_{\theta JA}$	Steady State, 62	$^\circ\text{C/W}$
Maximum Thermal Resistance Junction-Case ¹	$R_{\theta JC}$	5	

ELECTRICAL CHARACTERISTICS ($T_J=25^\circ\text{C}$ unless otherwise specified)

Parameter	Symbol	Min.	Typ.	Max.	Unit	Teat Conditions	
Drain-Source Breakdown Voltage	BV_{DSS}	30	-	-	V	$V_{GS}=0, I_D=250\mu\text{A}$	
Breakdown Voltage Temperature Coefficient	$\Delta BV_{DSS} / \Delta T_J$	-	0.023	-	V/ $^\circ\text{C}$	Reference to 25°C , $I_D=1\text{mA}$	
Gate-Threshold Voltage	$V_{GS(th)}$	1	-	2.5	V	$V_{DS}=V_{GS}, I_D=250\mu\text{A}$	
Forward Transconductance	g_{fs}	-	21.6	-	S	$V_{DS}=5\text{V}, I_D=15\text{A}$	
Gate-Source Leakage Current	I_{GSS}	-	-	± 100	nA	$V_{GS}=\pm 20\text{V}$	
Drain-Source Leakage Current	I_{DSS}	$T_J=25^\circ\text{C}$	-	-	1	μA	$V_{DS}=24\text{V}, V_{GS}=0$
		$T_J=55^\circ\text{C}$	-	-	5		$V_{DS}=24\text{V}, V_{GS}=0$
Static Drain-Source On-Resistance ²	$R_{DS(ON)}$	-	15	18	m Ω	$V_{GS}=10\text{V}, I_D=15\text{A}$	
		-	22	30		$V_{GS}=4.5\text{V}, I_D=10\text{A}$	
Gate Resistance	R_g	-	2.5	-	Ω	$V_{DS}=V_{GS}=0, f=1\text{MHz}$	
Total Gate Charge	Q_g	-	6.2	-	nC	$I_D=15\text{A}$ $V_{DS}=15\text{V}$ $V_{GS}=4.5\text{V}$	
Gate-Source Charge	Q_{gs}	-	2.4	-			
Gate-Drain ("Miller") Charge	Q_{gd}	-	2.5	-			
Turn-on Delay Time ²	$T_{d(on)}$	-	3	-	nS	$V_{DD}=15\text{V}$ $I_D=15\text{A}$ $V_{GS}=10\text{V}$ $R_G=3.3\Omega$	
Rise Time	T_r	-	7.6	-			
Turn-off Delay Time	$T_{d(off)}$	-	21	-			
Fall Time	T_f	-	4	-			
Input Capacitance	C_{iss}	-	572	-	pF	$V_{GS}=0$ $V_{DS}=15\text{V}$ $f=1\text{MHz}$	
Output Capacitance	C_{oss}	-	81	-			
Reverse Transfer Capacitance	C_{rss}	-	65	-			
Source-Drain Diode							
Diode Forward Voltage ²	V_{SD}	-	-	1.2	V	$I_S=1\text{A}, V_{GS}=0, T_J=25^\circ\text{C}$	
Continuous Source Current ¹⁴	I_S	-	-	30	A	$V_D=V_G=0, \text{Force Current}$	
Pulsed Source Current ²⁴	I_{SM}	-	-	60			
Reverse Recovery Time	t_{rr}	-	17	-	nS	$I_F=15\text{A}, dI/dt=100\text{A}/\mu\text{s}$	
Reverse Recovery Charge	Q_{rr}	-	3	-	nC	$T_J=25^\circ\text{C}$	

Notes:

1. The data tested by surface mounted on a 1 inch² FR-4 board with 20Z copper.
2. The data tested by pulsed , Pulse Width $\leq 300\mu\text{s}$, Duty Cycle $\leq 2\%$.
3. The power dissipation is limited by 150°C junction temperature.
4. The data is theoretically the same as I_D and I_{DM} , in real applications, should be limited by total power dissipation.

CHARACTERISTIC CURVES

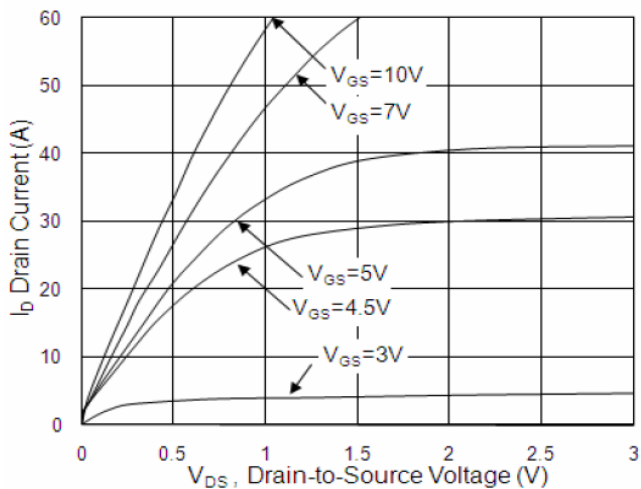


Fig.1 Typical Output Characteristics

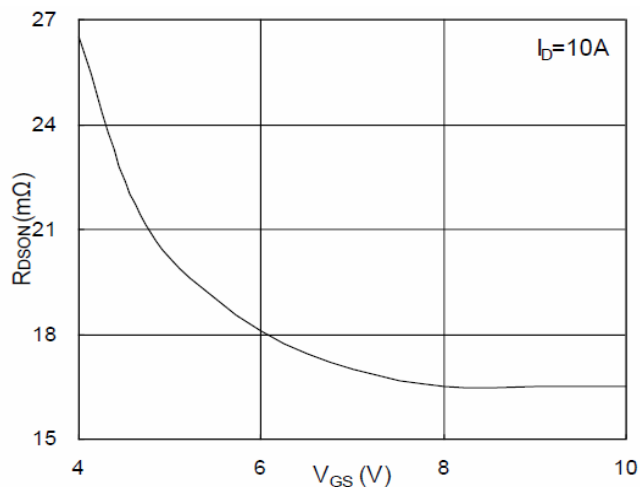


Fig.2 On-Resistance v.s Gate-Source

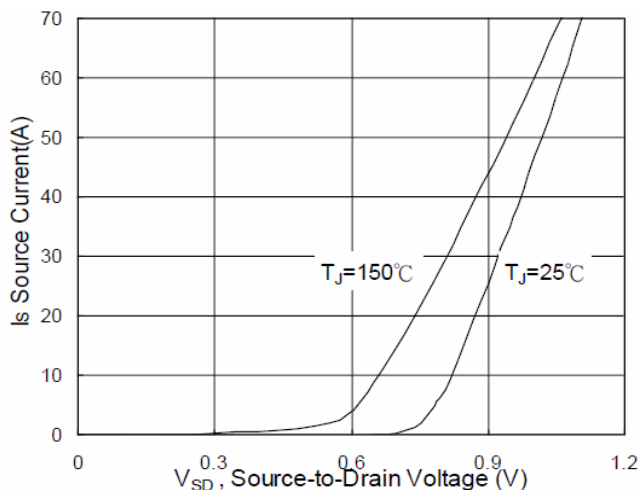


Fig.3 Forward Characteristics Of Reverse

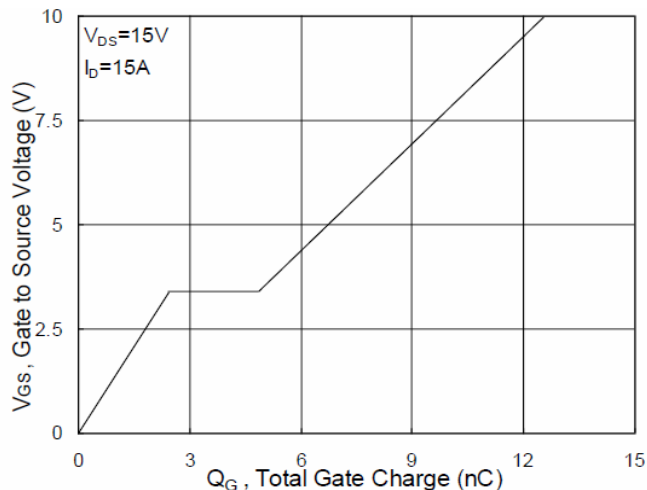


Fig.4 Gate-Charge Characteristics

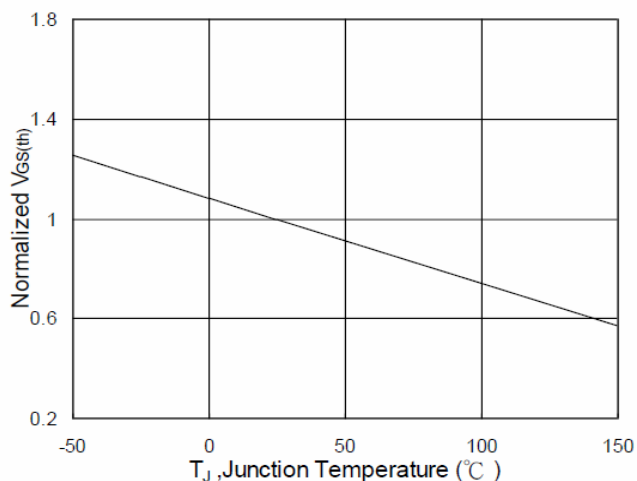


Fig.5 Normalized $V_{GS(th)}$ v.s T_J

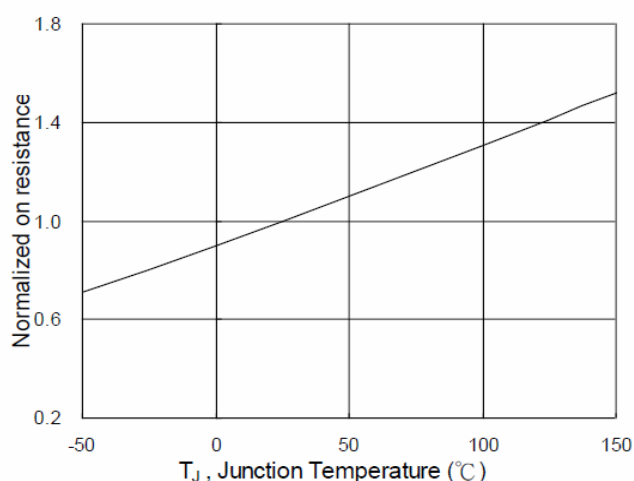


Fig.6 Normalized $R_{DS(ON)}$ v.s T_J

CHARACTERISTIC CURVES

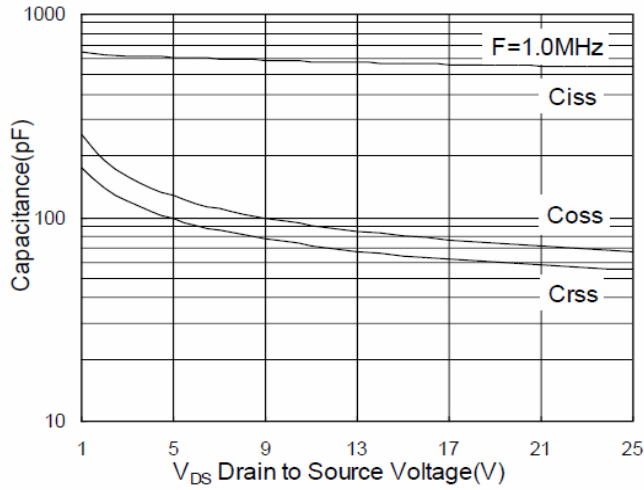


Fig.7 Capacitance

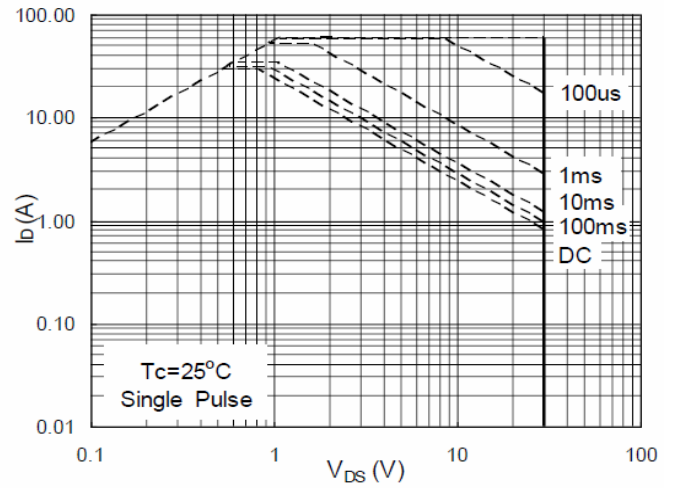


Fig.8 Safe Operating Area

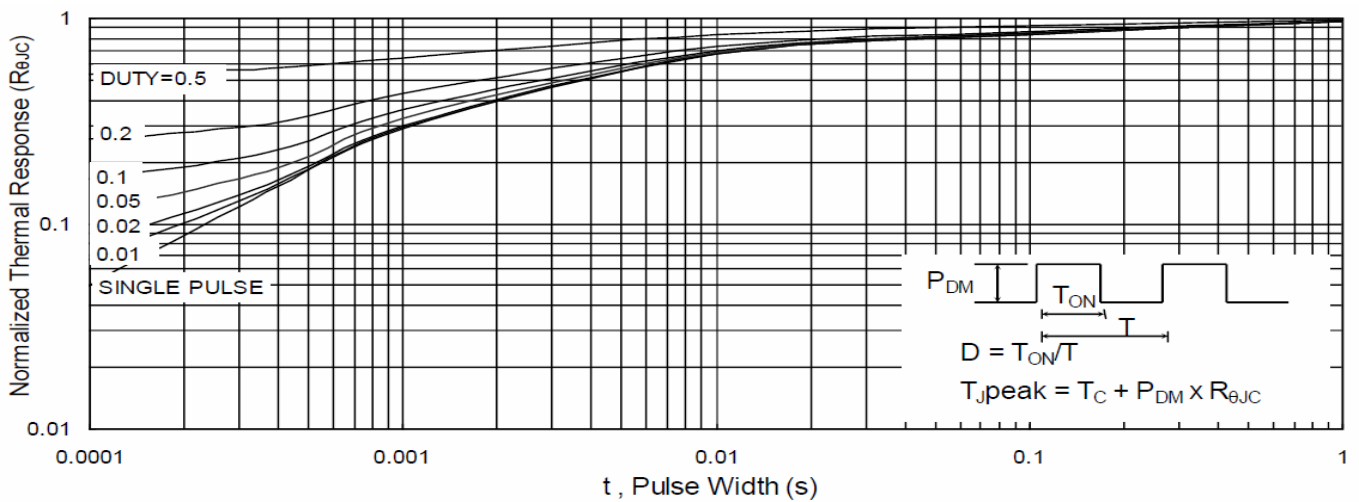


Fig.9 Normalized Maximum Transient Thermal Impedance

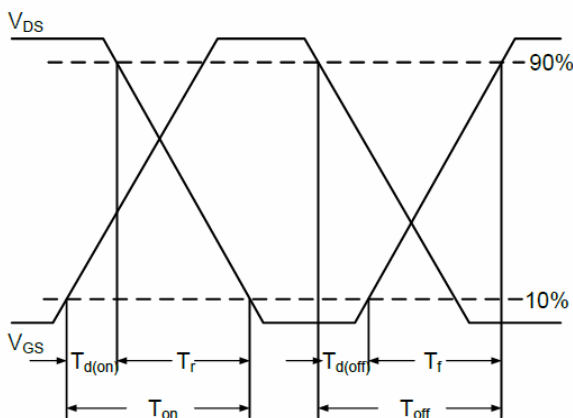


Fig.10 Switching Time Waveform

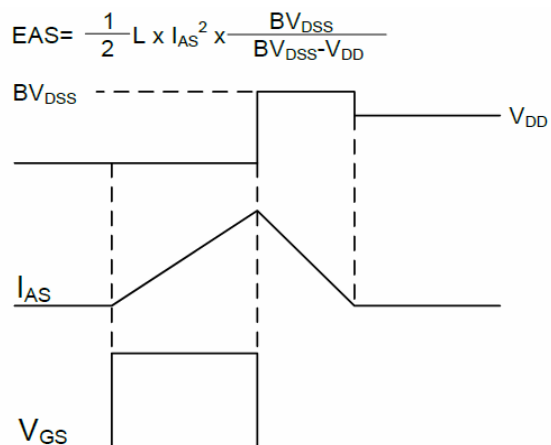


Fig.11 Unclamped Inductive Switching Waveform